

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L5	3762	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((angle slope) with (reflect reflection reflecting reflected) with (light beam ray illumination beaming illuminating)) and ((perpendicular vertical upright) near3 (surface exterior sample specimen wafer die))	US-PGPUB; USPAT	OR	ON	2005/03/24 10:12
L6	190	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((angle slope) with (reflect reflection reflecting reflected) with (light beam ray illumination beaming illuminating)) and ((perpendicular vertical upright) near3 (surface exterior sample specimen wafer die))	USOCR; IBM_TDB	OR	ON	2005/03/24 07:12
L8	1667	((measure measuring measured measurement determine determined determination determining analyze analyse analysis analyzing analysing test tested testing analysed analyzed) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and ((two pair couple duo dual twin binary twofold double multiple many several) with (light ray beam beaming lamp radiation irradiation irradiating radiating illuminating illumination shining beamed irradiated illuminated radiated) with (perpendicular perpendicularity upright uprightness vertical verticalness verticality perpendicularity vertically perpendicularly))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 07:28

L11	92	((measure measuring measured measurement determine determined determination determining analyze analyse analysis analyzing analysing test tested testing analysed analyzed) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and ((two pair couple duo dual twin binary twofold double multiple many several) with (light ray beam beaming lamp radiation irradiation irradiating radiating illuminating illumination shining beamed irradiated illuminated radiated) with (perpendicular perpendicularity upright uprightness vertical verticalness verticality perpendicularity vertically perpendicularly)) and ((extrapolate extrapolating extrapolation compute computed computing computation calculate calculated calculation calculating) with (angle angularity slope obliqueness obliquity) with (reflect reflected reflection reflecting))	US-PGPUB; USPAT	OR	ON	2005/03/24 07:46
L17	83	(((illuminat\$3 light beam\$3 radiat\$3 irradiat\$3) near3 (surface exterior sample specimen wafer die)) with ((pair double twin duo dual couple two several many multiple) near3 (lamp light laser))) and (((zero null negative no) near3 reflect\$4 near3 (angle slope)))	US-PGPUB; USPAT	OR	ON	2005/03/24 08:03
L19	17037	((method\$5 system process procedure way algorithm) with (detect\$3 measur\$5 determin\$5 evaluat\$3 sens\$3) with ((surface exterior sample specimen) near3 (character\$5 feature irregularities irregularity roughness flatness smoothness planarity planar plane smooth flat topology topography topological topographical topologic topographic)))	US-PGPUB; USPAT	OR	ON	2005/03/24 08:14
L24	713	((light\$3 beam\$3 ray illuminat\$3 radiat\$3 irradiat\$3 lasing) adj (surface exterior sample specimen wafer die)) same ((two pair double duo dual binary) adj (lamp emitter laser light))	US-PGPUB; USPAT	OR	ON	2005/03/24 08:34
L25	9	(((light\$3 beam\$3 ray illuminat\$3 radiat\$3 irradiat\$3 lasing) adj (surface exterior sample specimen wafer die)) same (((two pair double duo dual binary) adj (lamp emitter laser light)) with ((perpendicular\$3 vertical\$4) near3 (surface exterior sample specimen wafer die))))	US-PGPUB; USPAT	OR	ON	2005/03/24 09:06
L26	1	"4988202".pn.	USPAT	OR	OFF	2005/03/24 09:08
L27	1	wo-200159404-\$.did.	DERWENT	OR	OFF	2005/03/24 09:09
L28	1	"20020093664"	US-PGPUB	OR	OFF	2005/03/24 09:11

L29	1	"6577404".pn.	USPAT	OR	OFF	2005/03/24 09:11
L30	105	356/603.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/24 09:21
L31	85	356/604.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/24 09:21
L32	599	356/446.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/24 09:22
L33	4	("4449818" "4677473" "4792696" "6177682").pn.	USPAT	OR	OFF	2005/03/24 09:23
L34	0	wo-199836240-\$.did.	DERWENT	OR	OFF	2005/03/24 09:24
L35	1	wo-200045125-\$.did.	DERWENT	OR	OFF	2005/03/24 09:26
L36	1	"6757065".pn.	USPAT	OR	OFF	2005/03/24 09:28
L37	10	("4162126" "5311286" "5463464" "5465153" "5835190" "5894348" "5930383" "6522777" "6549288" "6552783").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/03/24 09:30
L38	1	2000-135907.NRAN.	DERWENT	OR	OFF	2005/03/24 09:38
L39	0	("6757065").URPN.	USPAT	OR	OFF	2005/03/24 09:28
L41	4	("4162126" "5311286" "5463464" "5465153" "5835190" "5894348" "5930383" "6522777" "6549288" "6552783").PN. and ((two double twin binary multiple several many) adj (light lamp laser illuminator))	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/24 09:35
L46	32	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((angle slope) with (reflect reflection reflecting reflected) with (light beam ray illumination beaming illuminating)) and ((perpendicular vertical upright) near3 (surface exterior sample specimen wafer die))	EPO; JPO; DERWENT	OR	ON	2005/03/24 09:41
L47	0	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((angle slope) with (reflect reflection reflecting reflected) with (light beam ray illumination beaming illuminating)) and ((perpendicular vertical upright) near3 (surface exterior sample specimen wafer die)) and ((two duo dual double twin multiple several many) adj (light lamp laser))	EPO; JPO; DERWENT	OR	ON	2005/03/24 09:42

L48	953	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((angle slope) with (reflect reflection reflecting reflected) with (light beam ray illumination beaming illuminating)) and ((perpendicular vertical upright) near3 (surface exterior sample specimen wafer die)) and ((two duo dual double twin multiple several many) adj (light lamp laser))	US-PGPUB; USPAT	OR	ON	2005/03/24 09:43
L49	0	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((zero null minimum) adj (reflect reflection reflecting reflected) adj (angle slope)) and ((perpendicular vertical upright) near3 (surface exterior sample specimen wafer die)) and ((two duo dual double twin multiple several many) adj (light lamp laser))	US-PGPUB; USPAT	OR	ON	2005/03/24 09:45
L50	11	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((zero null minimum) near3 (reflect reflection reflecting reflected) near3 (angle slope)) and ((perpendicular vertical upright) near3 (surface exterior sample specimen wafer die)) and ((two duo dual double twin multiple several many) adj (light lamp laser))	US-PGPUB; USPAT	OR	ON	2005/03/24 09:52
L51	4	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and (imaginary adj (angle slope))	US-PGPUB; USPAT	OR	ON	2005/03/24 09:53
L52	1337	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((no null zero minimum minimal) adj reflect\$3)	US-PGPUB; USPAT	OR	ON	2005/03/24 09:54
L53	199	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((no null zero minimum minimal) adj reflect\$3) and (("at least two" two duo dual double twin duo many several multiple) adj (light lamp laser illuminator irradiator))	US-PGPUB; USPAT	OR	ON	2005/03/24 10:00

L54	7	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((no null zero minimum minimal) adj reflect\$3) and (((("at least two" two dual double twin duo many several multiple) adj (light lamp laser illuminator irradiator)) with (perpendicular normal vertical vertically perpendicularly)))	US-PGPUB; USPAT	OR	ON	2005/03/24 10:00
L55	0	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((no null zero minimum minimal) adj reflect\$3) and (((("at least two" two dual double twin duo many several multiple) adj (light lamp laser illuminator irradiator)) with (perpendicular normal vertical vertically perpendicularly)))	USOCR; IBM_TDB	OR	ON	2005/03/24 10:00
L56	0	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((no null zero minimum minimal) adj reflect\$3) and (((("at least two" two dual double twin duo many several multiple) adj (light lamp laser illuminator irradiator)) with (perpendicular normal vertical vertically perpendicularly)))	EPO; JPO; DERWENT	OR	ON	2005/03/24 10:00
L57	6	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((no null zero minimum minimal) adj reflect\$3) and (("at least two" two dual double twin duo many several multiple) adj (light lamp laser illuminator irradiator))	USOCR; IBM_TDB	OR	ON	2005/03/24 10:01
L58	1	((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness)) and ((no null zero minimum minimal) adj reflect\$3) and (("at least two" two dual double twin duo many several multiple) adj (light lamp laser illuminator irradiator))	EPO; JPO; DERWENT	OR	ON	2005/03/24 10:01

L59	1200	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus))	US-PGPUB; USPAT	OR	ON	2005/03/24 10:53
L60	1	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (imaginary near3 (angle slope) near3 incidence near3 (no zero none null) near3 reflection near3 detected)	US-PGPUB; USPAT	OR	ON	2005/03/24 10:53
L61	1	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus)) and (imaginary near3 (angle slope) near3 incidence near3 (no zero none null) near3 reflection)	US-PGPUB; USPAT	OR	ON	2005/03/24 10:54
L62	1	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus)) and ((imaginary near3 (angle slope)) with incidence with ((no zero none null) near3 reflection))	US-PGPUB; USPAT	OR	ON	2005/03/24 10:55
L63	1	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus)) and (imaginary with (angle slope) with incidence with (no zero none null) with reflection)	US-PGPUB; USPAT	OR	ON	2005/03/24 10:56

L64	1	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus)) and (imaginary same (angle slope) same incidence same (no zero none null) same reflection)	US-PGPUB; USPAT	OR	ON	2005/03/24 10:57
L65	28	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus)) and imaginary and (angle slope) and incidence and ((no zero none null) near3reflection)	US-PGPUB; USPAT	OR	ON	2005/03/24 11:04
L66	24	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus)) and (brewster near3 angle)	US-PGPUB; USPAT	OR	ON	2005/03/24 11:13
L67	0	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus)) and ((calculat\$3 comput\$5 determin\$5) near3 ((brewster near3 angle) ((no zero null) adj (reflect\$3)))) and imaginary	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 11:17
L68	1	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp) adj (beam ray source device apparatus)) and ((calculat\$3 comput\$5 determin\$5) near3 ((brewster near3 angle) ((no zero null) adj (reflect\$3))))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 11:19

L69	14	((detect\$3 evaluat\$3 measur\$5 determin\$5 test\$3 inspect\$3) with ((surface exterior sample specimen wafer die) near3 (feature character characteristic roughness topology topography smoothness planarity height regularity irregularity flatness))) and (("at least two" two several double multiple twin binary) adj (light laser lamp)) and (((brewster near3 angle) ((no zero null) adj (reflect\$3)))) and (height adj profile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 12:09
L70	0	((("at least two" two several double multiple twin binary) adj (light laser lamp)) near5 ((illuminat\$3 light\$3 irradiat\$3 radiat\$3) adj (surface exterior)) and ((light laser lamp) near3 (perpendicular\$3 normal vertical\$3) near3 (reference standard) adj (plane surface)) and (((control controller) adj unit) computer processor micro\$computer micro\$processor processor) near5 reflect\$3) and ((light laser radiat\$3 irradiat\$3 beam) near3 (detector sensor transducer)) and (imagin\$5 adj (angle slope)) and ((brewster near3 angle) ((no null zero) adj reflect\$3)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 12:21
L71	0	((("at least two" two several double multiple twin binary) adj (light laser lamp)) near5 ((illuminat\$3 light\$3 irradiat\$3 radiat\$3) adj (surface exterior)) and ((light laser lamp) near3 (perpendicular\$3 normal vertical\$3) near3 (reference standard) adj (plane surface)) and (((control controller) adj unit) computer processor micro\$computer micro\$processor processor) near5 reflect\$3) and ((light laser radiat\$3 irradiat\$3 beam) near3 (detector sensor transducer)) and (imagin\$5 adj (angle slope)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 12:21
L72	0	((("at least two" two several double multiple twin binary) adj (light laser lamp)) near5 ((illuminat\$3 light\$3 irradiat\$3 radiat\$3) adj (surface exterior)) and ((light laser lamp) near3 (perpendicular\$3 normal vertical\$3) near3 (reference standard) adj (plane surface)) and (((control controller) adj unit) computer processor micro\$computer micro\$processor processor)) and ((light laser radiat\$3 irradiat\$3 beam) near3 (detector sensor transducer)) and (imagin\$5 adj (angle slope)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 12:22

L73	0	((("at least two" two several double multiple twin binary) adj (light laser lamp)) near5 ((illuminat\$3 light\$3 irradiat\$3 radiat\$3) adj (surface exterior)) and ((light laser lamp) near3 (perpendicular\$3 normal vertical\$3) adj (plane surface)) and (((control controller) adj unit) computer processor micro\$computer micro\$processor processor)) and ((light laser radiat\$3 irradiat\$3 beam) near3 (detector sensor transducer)) and (imagin\$5 adj (angle slope))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 12:23
L74	1	((("at least two" two several double multiple twin binary) adj (light laser lamp)) near5 ((illuminat\$3 light\$3 irradiat\$3 radiat\$3) adj (surface exterior)) and ((light laser lamp) near3 (perpendicular\$3 normal vertical\$3) adj (plane surface)) and (((control controller) adj unit) computer processor micro\$computer micro\$processor processor)) and ((light laser radiat\$3 irradiat\$3 beam) near3 (detector sensor transducer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/03/24 13:19
L75	6	("4988202" "5077803" "5757474" "5835190" "5894348" "6271916" "6549288" "6552783" "6577404" "6606153" "6757065").pn. and ((two several both many multiple double binary pair) near3 (light laser irradiating irradiation radiating radiation illuminating illumination) near3 source)	USPAT	OR	ON	2005/03/24 13:39
L78	11	("4988202" "5077803" "5757474" "5835190" "5894348" "6271916" "6549288" "6552783" "6577404" "6606153" "6757065").pn.	USPAT	OR	ON	2005/03/24 13:33
S1	1432	250/306.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/24 06:50
S2	1181	250/307.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:27
S3	584	73/104.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:28
S4	1029	73/105.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:28
S5	222	73/432.1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:28
S6	508	73/865.8.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:28
S7	208	356/2.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:28
S8	841	356/237.1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:28
S9	744	356/237.2.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:28

S10	300	356/239.1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:28
S11	179	356/256.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S12	173	356/496.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S13	256	356/498.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S14	255	356/600.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S15	429	356/601.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/24 09:21
S16	96	356/612.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S17	469	700/95.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S18	342	700/110.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S19	460	700/117.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S20	162	700/118.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:29
S21	149	700/120.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30
S22	256	702/33.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30
S23	286	702/127.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30
S24	211	702/155.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30
S25	210	702/159.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30
S26	109	702/166.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30
S27	169	702/167.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30
S28	555	702/189.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30
S29	146	382/108.ccls.	US-PGPUB; USPAT	OR	OFF	2005/03/23 15:30

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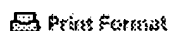
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1 Surface displacement mapping of piezoelectric multilayer actuators

Stewart, M.; Cain, M.G.; Battrick, W.;

Dielectric Materials, Measurements and Applications, 2000. Eighth International Conference on (IEE Conf. Publ. No. 473) , 17-21 Sept. 2000

Pages:445 - 447

[\[Abstract\]](#) [\[PDF Full-Text \(320 KB\)\]](#) **IEE CNF**

2 Measuring liquid properties with smooth- and textured-surface resonators

Martin, S.J.; Wessendorf, K.O.; Gebert, C.T.; Frye, G.C.; Cernosek, R.W.; Casaus, L.; Mitchell, M.A.;

Frequency Control Symposium, 1993. 47th., Proceedings of the 1993 IEEE International , 2-4 June 1993

Pages:603 - 608

[\[Abstract\]](#) [\[PDF Full-Text \(408 KB\)\]](#) **IEEE CNF**

3 Prediction of hilly terrain diffraction loss experienced by microwaves

Al-Nuaimi, M.O.; Ding, M.S.;

Diffraction Propagation Modelling Techniques Embracing Surface Feature Data, IEE Colloquium on , 16 Nov 1990

Pages:8/1 - 8/5

[\[Abstract\]](#) [\[PDF Full-Text \(248 KB\)\]](#) **IEE CNF**

4 Comparison of a polarimetric scattering and emission model with ocean backscatter and brightness measurements

Yueh, S.H.; Nghiem, S.V.; Kwok, R.;

Geoscience and Remote Sensing Symposium, 1994. IGARSS '94. 'Surface and Atmospheric Remote Sensing: Technologies, Data Analysis and Interpretation', International , Volume: 1 , 8-12 Aug. 1994

Pages:258 - 260 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(264 KB\)\]](#) IEEE CNF

5 Automatic programming of coordinate measuring machines

Spyridi, A.J.; Requicha, A.A.G.;

Robotics and Automation, 1994. Proceedings., 1994 IEEE International Conference on , 8-13 May 1994

Pages:1107 - 1112 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(492 KB\)\]](#) IEEE CNF

6 Measurement and classification of low-grazing-angle radar sea spikes

Liu, Y.; Frasier, S.J.; McIntosh, R.E.;

Antennas and Propagation, IEEE Transactions on , Volume: 46 , Issue: 1 , Jan. 1998

Pages:27 - 40

[\[Abstract\]](#) [\[PDF Full-Text \(352 KB\)\]](#) IEEE JNL

7 Image processing for a scanning acoustic microscope that measures amplitude and phase

Reinholdtsen, P.A.; Khuri-Yakub, B.T.;

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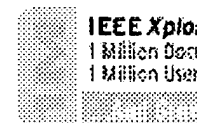
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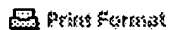
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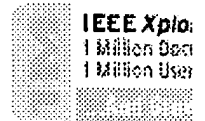
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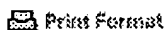
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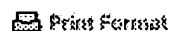
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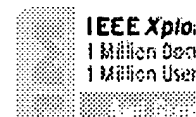
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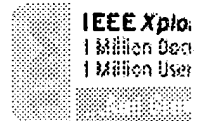
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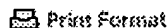
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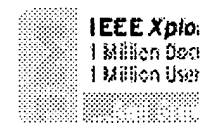
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(irregularity <or>
characteristics <or>
features)) <and> ((zero <or>
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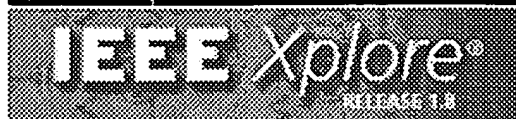
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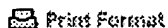
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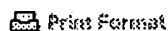
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